



INTERNATIONAL
ACCREDITATION
SERVICE®

CERTIFICATE OF ACCREDITATION

This is to attest that

SEOUL SEMICONDUCTOR TESTING LABORATORY

97-11, SANDAN-RO 163BEON-GIL, DANWON-GU, ANSAN-SI
GYEONGGI-DO, 15429 SOUTH KOREA

Testing Laboratory TL-688

has met the requirements of AC89, *IAS Accreditation Criteria for Testing Laboratories*, and has demonstrated compliance with ISO/IEC Standard 17025:2017, *General requirements for the competence of testing and calibration laboratories*. This organization is accredited to provide the services specified in the scope of accreditation.

Effective Date May 22, 2024



A handwritten signature in black ink, reading "Raj Nathan".

President

Visit www.iasonline.org for current accreditation information.

SCOPE OF ACCREDITATION

International Accreditation Service, Inc.

3060 Saturn Street, Suite 100, Brea, California 92821, U.S.A. | www.iasonline.org

SEOUL SEMICONDUCTOR TESTING LABORATORY

www.seoulsemicon.com

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Contact Phone +82-1087385476

Accredited to ISO/IEC 17025:2017

Effective Date May 22, 2024

Electronic	
AEC-Q102	Failure Mechanism based Stress Test Qualification for Optoelectronic Semiconductors in Automotive Applications (Excluded the qualification test methods: A2c, A3b, B1c, C1-C6 & C8-C14, E3 & E4, G1-G4)
AEC-Q102-001	DEW Test
ANSI/IES LM-80-15	Measuring Flux and Color Maintenance of LED Packages, Arrays and Modules
ANSI/IES TM-21-19	Projecting Long Term Lumen, Photon and Radiant Flux Maintenance of LED Light Sources
ANSI/IES TM-35-19	Projecting Long Term Chromaticity Coordinate Shift of LED Packages, Arrays and Modules
CIE 127:2007	Measurements of LEDs
IES LM-80-08	Measuring Lumen Maintenance of LED Light Sources
IES TM-21-11	Projecting Long Term Lumen Maintenance of LED Light Sources
JEDEC JESD22-A101	Steady-State Temperature-Humidity Bias Life Test
JEDEC JESD22-A104	Temperature Cycling
JEDEC JESD22-A105	Power and Temperature Cycling
JEDEC JESD22-A108	Temperature, Bias, and Operating Life
JEDEC JESD22-A113	Preconditioning of Nonhermetic Surface Mount Devices Prior to Reliability Testing
JEDEC JESD22-B101	External Visual